

Notice of References Cited	Application/Control No. 10/673,507	Applicant(s)/Patent Under Reexamination STRANG, ERIC J.	
	Examiner Akash Saxena	Art Unit 2128	Page 1 of 1


U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Su-shing Chen, "AEMPES: An expert system for in-situ diagnostics and process monitoring" addressing the on-tool simulation; IEEE 1990 paper <i>pp. 119-122</i> 			
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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